Search Notes



Application/Control N

10/712,687 Examiner

Jianchun Qin

Applicant(s)/Patent under Reexamination

MIWA, AKIHIRO

Art Unit

2837

	SEAR	CHED	
Class	Subclass	Date	Examiner
84	600,615, 645		TO
	470,477R		
345	157		
715	856	7/6/2005	56

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST Text Search	7/06/05	JQ	
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